

# N-Channel 30 V (D-S) MOSFET

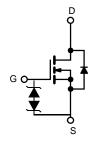
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ.)		
30	$0.0014 \text{ at V}_{GS} = 10 \text{ V}$	65	75 nC		
30	0.0017 at V <sub>GS</sub> = 4.5 V	50	75 110		

### **FEATURES**

- DT-Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested
- Typical ESD protection

### **APPLICATIONS**

- · Notebook PC Core
- VRM/POL



N-Channel MOSFET

DFN 2x	2
Top View	Bottom View
Pin 1	S D D Pin 1

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	30	V	
Gate-Source Voltage		$V_{GS}$	± 20	V	
	T <sub>C</sub> = 25 °C		65 <sup>a, e</sup>		
Continuous Drain Current (T. – 175 °C)	T <sub>C</sub> = 70 °C	-	54 <sup>e</sup>		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	33 <sup>b, c</sup>	A	
	T <sub>A</sub> = 70 °C		28.8 <sup>b, c</sup>		
Pulsed Drain Current	•	I <sub>DM</sub>	260		
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	63		
Single Pulse Avalanche Energy	L = 0.1 IIII1	E <sub>AS</sub>	110	mJ	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	65 <sup>a, e</sup>	А	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	3	35 <sup>b, c</sup>	7	
	T <sub>C</sub> = 25 °C		89		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	56	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	ı D	7.65 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		4.85 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	15	20	°C/W		
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	1.1	1.5	· C/VV		

### Notes:

- a. Based on T<sub>C</sub> = 25 °C. b. Surface mounted on 1" x 1" FR4 board.

- d. Maximum under steady state conditions is 90 °C/W. e. Calculated based on maximum junction temperature.



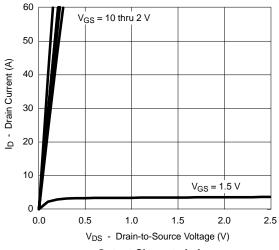
Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		35		m\//°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	ι <sub>D</sub> = 250 μΑ		- 5.5		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.5		1.4	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	1 10 μΑ	
		V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	70			Α	
Drain-Source On-State Resistance <sup>a</sup>		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		0.0014	0.0020	Ω	
	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		0.0017	0.0022		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 24 V, I <sub>D</sub> = 10 A		100		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			3859		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		996			
Reverse Transfer Capacitance	C <sub>rss</sub>			300			
Total Gate Charge	Qg	$V_{DS} = 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		75		nC	
Iolai Gale Charge				63.5			
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 24V$ , $V_{GS} = 4.5 V$ , $I_D = 8 A$		35			
Gate-Drain Charge	$Q_{gd}$			30			
Gate Resistance	$R_g$	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			18	27		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 24V, R $_{L}$ = 0.555 $\Omega$		11	17	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		70	105		
Fall Time	t <sub>f</sub>			10	15		
Turn-On Delay Time	t <sub>d(on)</sub>			55	83		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 24 V, $R_L$ = 0.625 $\Omega$		180	270		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 8 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		55	83		
Fall Time	t <sub>f</sub>			12	18		
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			65	А	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				260	^	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 8 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			52	78	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 10 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	ta	$_{1F} - 10 \text{ A}$ , $_{UV}$		27			
Reverse Recovery Rise Time	t <sub>b</sub>	7		25		ns	

#### Notes:

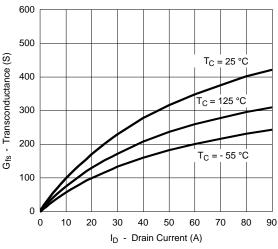
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

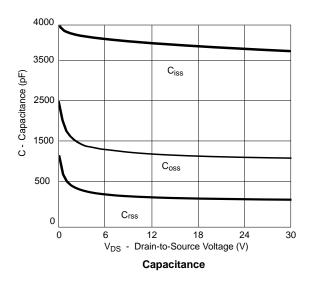
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

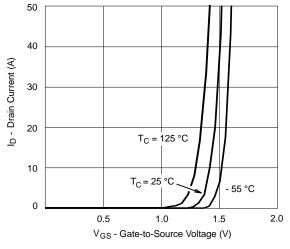


### **Output Characteristics**

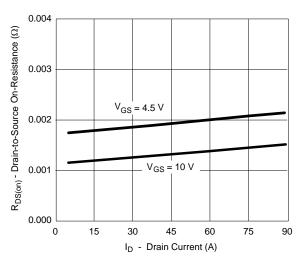


Transconductance

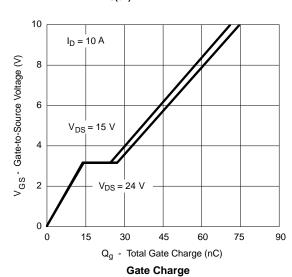




**Transfer Characteristics** 

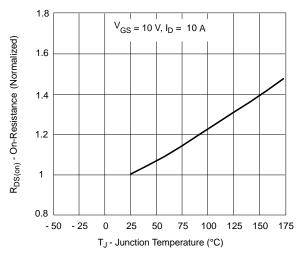


R<sub>DS(on)</sub> vs. Drain Current

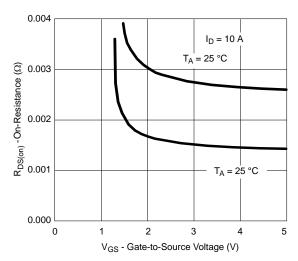




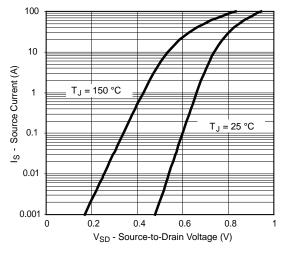
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



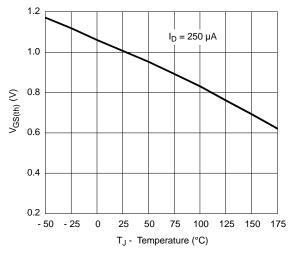
On-Resistance vs. Junction Temperature



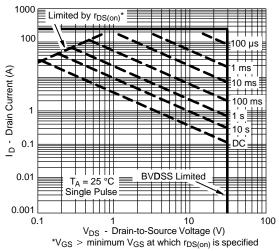
 $R_{DS(on)}$  vs.  $V_{GS}$  vs. Temperature



Forward Diode Voltage vs. Temperature

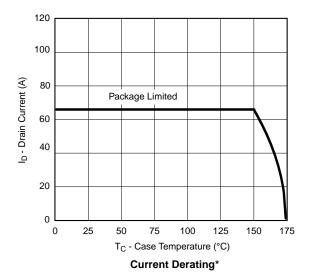


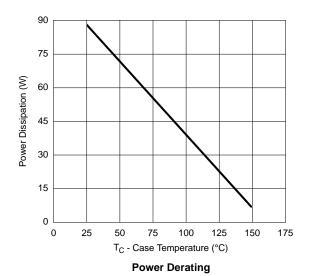
Threshold Voltage



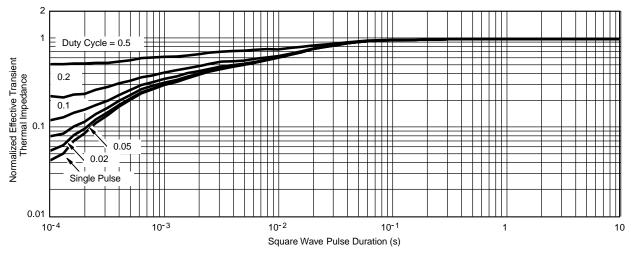
Safe Operating Area, Junction-to-Ambient

### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case





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